

# ***N tice of R ferenc s Cited***

Application/Control No.

09/695,317

Applicant(s)/Patent Under  
Reexamination  
YAMADA ET AL.

Examiner

Robert D. Harlan

Art Unit

1713

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,380,288	04-2002	Hojo et al.	152/450
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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## **NON-PATENT DOCUMENTS**

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